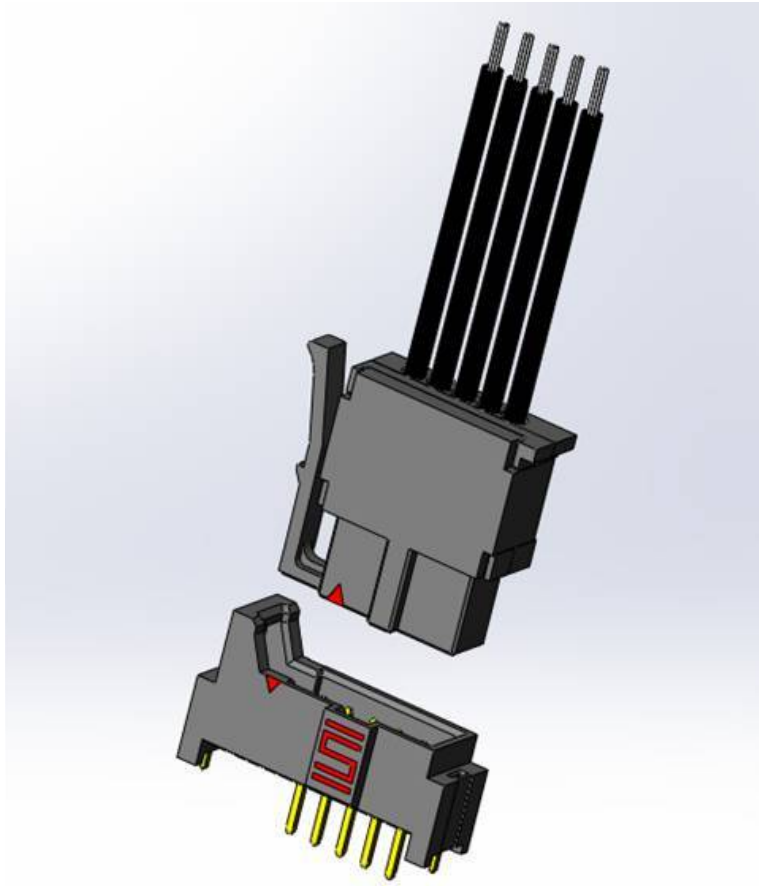




Project Number: Design Qualification Test Report	Tracking Code: 321945_Report_Rev_1
Requested by: Steven Xu	Date: 7/23/2014
Part #: I2SS-05-24-T/T2I-05-VT-T-S-TH	
Part description: I2SS/T2I	Tech: Kason He
Test Start: 03/21/2014	Test Completed: 05/08/2014



**DESIGN QUALIFICATION TEST REPORT**

**I2SS/T2I**

**I2SS-05-24-T/T2I-05-VT-T-S-TH**

**REVISION HISTORY**

<b>DATA</b>	<b>REV.NUM.</b>	<b>DESCRIPTION</b>	<b>ENG</b>
<b>07/17/2014</b>	<b>1</b>	<b>Initial Issue</b>	<b>KH</b>

## CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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### SCOPE

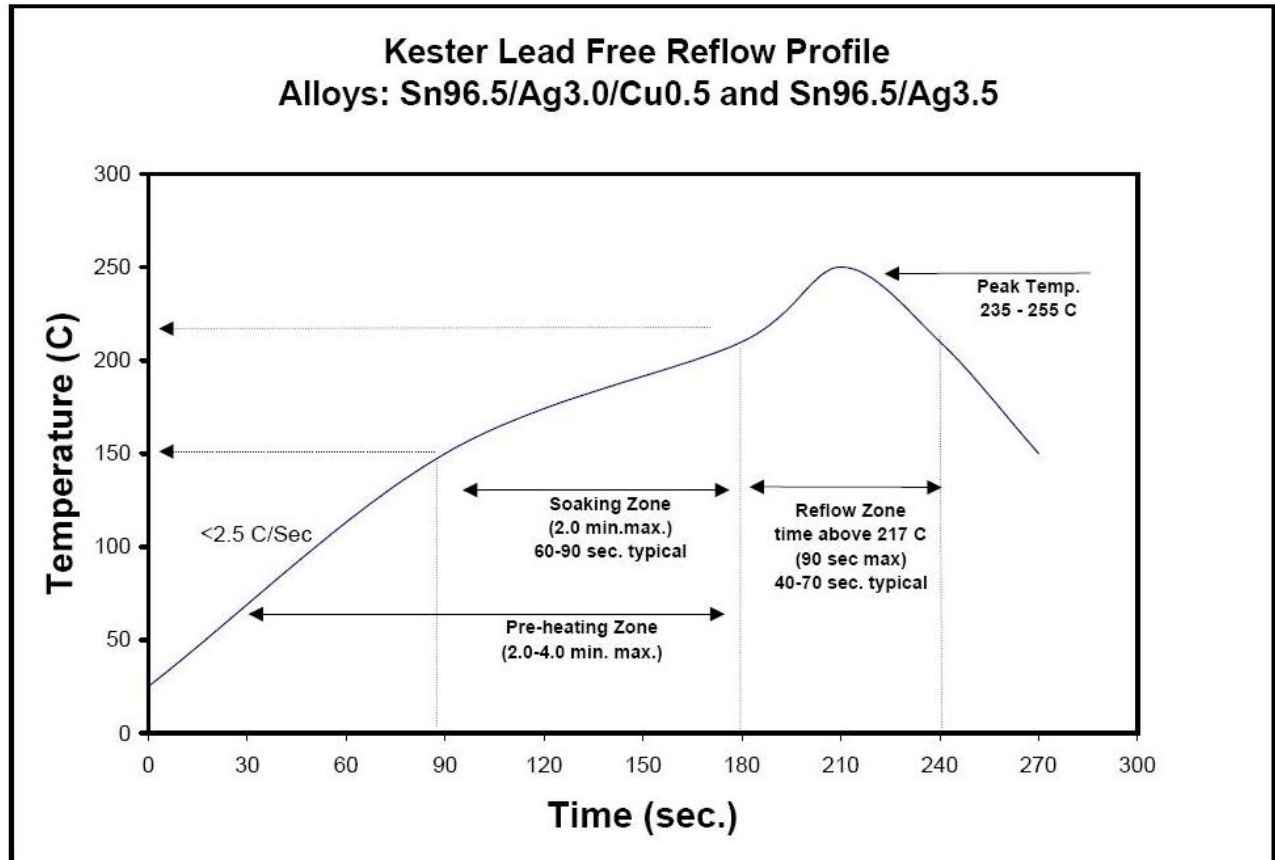
To perform the following tests: Design Qualification test. Please see test plan.

### APPLICABLE DOCUMENTS

Standards: EIA Publication 364

### TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-105941-TST/PCB-105943-TST/PCB-105944-TST/ PCB-105942-TST

**TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)**

**FLOWCHARTS****Gas Tight**Group 1

I2SS-05-24-T

T2I-05-VT-T-S-TH

8 Assemblies

**Step Description**

1. LLCR <sup>(2)</sup>  
Max Delta = 15 mOhm
2. Gas Tight <sup>(1)</sup>
3. LLCR <sup>(2)</sup>  
Max Delta = 15 mOhm

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

**Normal Force**Group 1

I2SS-05-24-T

8 Contacts Minimum  
Signal Without Thermals

**Step Description**

1. Contact Gaps
2. Normal Force <sup>(1)</sup>  
Deflection = 0.004 "  
Expected Force at Max Deflection = 650 g

Group 2

I2SS-05-24-T

T2I-05-VT-T-S-TH

8 Contacts Minimum  
Signal With Thermals

**Step Description**

1. Contact Gaps
2. Thermal Age <sup>(2)</sup>
3. Contact Gaps
4. Normal Force <sup>(1)</sup>  
Deflection = 0.004 "  
Expected Force at Max Deflection = 650 g

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)  
Time Condition = B (250 Hours)

**FLOWCHARTS Continued****Thermal Aging**Group 1

I2SS-05-24-T

T2I-05-VT-T-S-TH

8 Assemblies

---

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force <sup>(2)</sup>
3.	LLCR <sup>(1)</sup> Max Delta = 15 mOhm
4.	Thermal Age <sup>(3)</sup>
5.	LLCR <sup>(1)</sup> Max Delta = 15 mOhm
6.	Mating/Unmating Force <sup>(2)</sup>
7.	Contact Gaps

---

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

**FLOWCHARTS Continued****Mating/Unmating/Durability**Group 1

I2SS-05-24-T

T2I-05-VT-T-S-TH

8 Assemblies

Step	Description
1.	Contact Gaps
2.	LLCR (2) Max Delta = 15 mOhm
3.	Mating/Unmating Force (3)
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force (3)
6.	Cycles Quantity = 25 Cycles
7.	Mating/Unmating Force (3)
8.	Cycles Quantity = 25 Cycles
9.	Mating/Unmating Force (3)
10.	Cycles Quantity = 25 Cycles
11.	Mating/Unmating Force (3)
12.	Contact Gaps
13.	LLCR (2) Max Delta = 15 mOhm
14.	Thermal Shock (4)
15.	LLCR (2) Max Delta = 15 mOhm
16.	Humidity (1)
17.	LLCR (2) Max Delta = 15 mOhm
18.	Mating/Unmating Force (3)

Group 2

I2SS-02-24-T

T2I-02-VT-T-S-TH

8 Assemblies

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force (3)
3.	Cycles Quantity = 25 Cycles
4.	Mating/Unmating Force (3)
5.	Cycles Quantity = 25 Cycles
6.	Mating/Unmating Force (3)
7.	Cycles Quantity = 25 Cycles
8.	Mating/Unmating Force (3)
9.	Cycles Quantity = 25 Cycles
10.	Mating/Unmating Force (3)

(1) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25oC to +65tC @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55oC to +85tC)

Test Duration = A-3 (100 Cycles)

**FLOWCHARTS Continued****IR/DWV****Pin-to-Pin**Group 1

I2SS-05-24-T  
T2I-05-VT-T-S-TH  
2 Assemblies

Group 2

I2SS-05-24-T  
  
2 Assemblies

Group 3

T2I-05-VT-T-S-TH  
2 Assemblies

Group 4

I2SS-05-24-T  
T2I-05-VT-T-S-TH  
2 Assemblies

**Step Description**

1. DWV Breakdown (2)

**Step Description**

1. DWV Breakdown (2)

**Step Description**

1. DWV Breakdown (2)

**Step Description**

1. IR (4)  
2. DWV at Test Voltage (1)  
3. Thermal Shock (5)  
4. IR (4)  
5. DWV at Test Voltage (1)  
6. Humidity (3)  
7. IR (4)  
8. DWV at Test Voltage (1)

- (1) DWV at Test Voltage = EIA-364-20  
Test Condition = 1 (Sea Level)  
DWV test voltage is equal to 75% of the lowest breakdown voltage  
Test voltage applied for 60 seconds
- (2) DWV Breakdown = EIA-364-20  
Test Condition = 1 (Sea Level)  
DWV test voltage is equal to 75% of the lowest breakdown voltage  
Test voltage applied for 60 seconds
- (3) Humidity = EIA-364-31  
Test Condition = B (240 Hours)  
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)  
Test Exceptions: ambient pre-condition and delete steps 7a and 7b
- (4) IR = EIA-364-21  
Test Condition = 500 Vdc, 2 Minutes Max
- (5) Thermal Shock = EIA-364-32  
Exposure Time at Temperature Extremes = 1/2 Hour  
Method A, Test Condition = I (-55°C to +85°C)  
Test Duration = A-3 (100 Cycles)

**FLOWCHARTS Continued****Current Carrying Capacity**

Group 1  
I2SS-05-24-T  
T2I-05-VT-T-S-TH  
1 Pins Powered  
Cable-24 AWG

Step	Description
1.	CCC (1) Rows = 1 Number of Positions = 1

Group 2  
I2SS-05-24-T  
T2I-05-VT-T-S-TH  
2 Pins Powered  
Cable-24 AWG

Step	Description
1.	CCC (1) Rows = 1 Number of Positions = 2

Group 3  
I2SS-05-24-T  
T2I-05-VT-T-S-TH  
3 Pins Powered  
Cable-24 AWG

Step	Description
1.	CCC (1) Rows = 1 Number of Positions = 3

Group 4  
I2SS-05-24-T  
T2I-05-VT-T-S-TH  
4 Pins Powered  
Cable-24 AWG

Step	Description
1.	CCC (1) Rows = 1 Number of Positions = 4

Group 5  
I2SS-05-24-T  
T2I-05-VT-T-S-TH  
5 Pins Powered  
Cable-24 AWG

Step	Description
1.	CCC (1) Rows = 1 Number of Positions = 5

(1) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

**FLOWCHARTS Continued****Mechanical Shock/Random Vibration/LLCR**Group 1

I2SS-05-24-T

T2I-05-VT-T-S-TH

8 Assemblies

**Step Description**

1. LLCR (1)  
Max Delta = 15 mOhm
2. Mechanical Shock (2)
3. Random Vibration (3)
4. LLCR (1)  
Max Delta = 15 mOhm

**(1) LLCR = EIA-364-23**

Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

**(2) Mechanical Shock = EIA-364-27**

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)  
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

**(3) Random Vibration = EIA-364-28**

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

**Mechanical Shock/Random Vibration/Event Detection**Group 1

I2SS-05-24-T

T2I-05-VT-T-S-TH

32 Points

**Step Description**

1. Nanosecond Event Detection  
(Mechanical Shock) (1)
2. Nanosecond Event Detection  
(Random Vibration) (2)

**(1) Nanosecond Event Detection (Mechanical Shock)**

Use EIA-364-87 for Nanosecond Event Detection:  
Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-27 for Mechanical Shock:

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)  
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

**(2) Nanosecond Event Detection (Random Vibration)**

Use EIA-364-87 for Nanosecond Event Detection:  
Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-28 for Random Vibration:

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

**FLOWCHARTS Continued****Cable Pull**

<u>Group 1</u>		<u>Group 2</u>	
I2SS-05-24-T		I2SS-05-24-T	
T2I-05-VT-T-S-TH		T2I-05-VT-T-S-TH	
5 Assemblies		5 Assemblies	
0 Degrees		90 Degrees	
Step	Description	Step	Description
1.	Cable Pull (1)	1.	Cable Pull (1)

- 
- (1) Cable Pull = EIA-364-38  
 Measure and Record Force Required to Failure  
 Failure = Discontinuity >1 microsecond at 10 ohms

**Cable Flex**

*Note: DWV to be performed at Test Voltage, DWV test voltage is equal to 75% of the lowest break down voltage from 'IR/DWV group 1~3'*

<u>Group 1</u>	
I2SS-05-24-T	
T2I-05-VT-T-S-TH	
8 Assemblies	
Flat Cable	
Step	Description
1.	IR (3)
2.	DWV at Test Voltage (2) Test Voltage = 300 V
3.	Cable Flex (1)
4.	Visual Inspection
5.	IR (3)
6.	DWV at Test Voltage (2) Test Voltage = 300 V

- 
- (1) Cable Flex = EIA-364-41  
 Circular Jacket Cable - to be tested 90° each direction (180° total)  
 Flat Cable - to be tested 70° each direction (140° total)  
 Monitor continuity during flex testing  
 Failure = Discontinuity >1 microsecond at 10 ohms
- (2) DWV at Test Voltage = EIA-364-20  
 Test Condition = 1 (Sea Level)  
 DWV test voltage is equal to 75% of the lowest breakdown voltage  
 Test voltage applied for 60 seconds
- (3) IR = EIA-364-21  
 Test Condition = 500 Vdc, 2 Minutes Max

## ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

### THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

### THERMAL:

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition 4 at 105° C
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

### HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

### MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

### VIBRATION:

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G<sup>2</sup> / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

### NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

### MATING/UNMATING:

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes.

**TEMPERATURE RISE (Current Carrying Capacity, CCC):**

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of  $I^2R$  (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
  - a. Self heating (resistive)
  - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
  - a. Ambient
  - b. 65° C
  - c. 75° C
  - d. 95° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

**LLCR:**

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms: ----- Unstable
  - f.  $>+2000$  mOhms:----- Open Failure

### ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

#### GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms: ----- Unstable
  - f.  $>+2000$  mOhms:----- Open Failure
- 4) Procedure:
  - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
  - b. Test Conditions:
    - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
    - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
    - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
    - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
    - v. Exposure time, 55 to 65 minutes.
    - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
    - vii. The samples shall be dried after exposure for a minimum of 1 hour.
    - viii. Drying temperature  $50^{\circ}$  C
    - ix. The final LLCR shall be conducted within 1 hour after drying.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes

**NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):**

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the connector housing.
- 3) If necessary, a "window" shall be made in the connector body to allow a probe to engage and deflect the contact at the same attitude and distance (plus 0.05 mm [0.002"]) as would occur in actual use.
- 4) The connector housing shall be placed in a holding fixture that does not interfere with or otherwise influence the contact force or deflection.
- 5) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC<sup>2</sup>, computer controlled test stand with a deflection measurement system accuracy of 5.0  $\mu\text{m}$  (0.0002").
- 6) The nominal deflection rate shall be 5 mm (0.2")/minute.
- 7) Unless otherwise noted a minimum of five contacts shall be tested.
- 8) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 9) The system shall utilize the TC<sup>2</sup> software in order to acquire and record the test data.
- 10) The permanent set of each contact shall be measured within the TC<sup>2</sup> software.
- 11) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes

**INSULATION RESISTANCE (IR):**

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
  - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
  - b. Test Conditions:
    - i. Between Adjacent Contacts or Signal-to-Ground
    - ii. Electrification Time 2.0 minutes
    - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) PROCEDURE:
  - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
  - b. Test Conditions:
    - i. Between Adjacent Contacts or Signal-to-Ground
    - ii. Barometric Test Condition 1
    - iii. Rate of Application 500 V/Sec
    - iv. Test Voltage (VAC) until breakdown occurs
- 2) MEASUREMENTS/CALCULATIONS
  - a. The breakdown voltage shall be measured and recorded.
  - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
  - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes

**CONNECTOR PULL:**

- 1) Secure cable near center and pull on connector
  - a. At 90°, right angle to cable
  - b. At 0°, in-line with cable

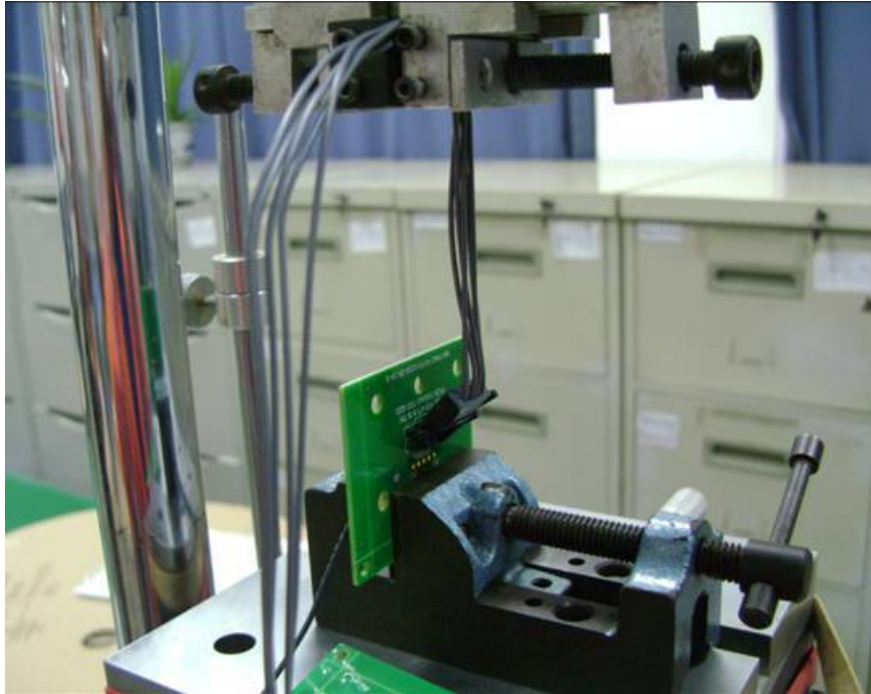


Fig. 1

(Typical set-up, actual part not depicted.)

90° Connector pull, notice the electrical continuity hook-up wires.

**ATTRIBUTE DEFINITIONS Continued**

The following is a brief, simplified description of attributes

**CABLE DURABILITY:**

- a. 140° Flex Mode, bend up to 500 cycles with 10 oz. load on cable end.



Fig. 2  
(Typical set-up, actual part not depicted.)

## RESULTS

### Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise -----4.7 A per contact with 1 contacts (1 x 1) powered
- CCC for a 30°C Temperature Rise -----3.9 A per contact with 2 contacts (1 x 2) powered
- CCC for a 30°C Temperature Rise -----3.3 A per contact with 3 contacts (1 x 3) powered
- CCC for a 30°C Temperature Rise -----3.0 A per contact with 4 contacts (1 x 4) powered
- CCC for a 30°C Temperature Rise -----2.8 A per contact with 5 contacts (1 x 5) powered

### Mating/Unmating Forces

#### Thermal Aging Group

- **Initial**
  - **Mating**
    - **Min** ----- 4.33 Lbs
    - **Max** ----- 4.52 Lbs
  - **Unmating**
    - **Min** ----- 3.37 Lbs
    - **Max** ----- 3.77 Lbs
- **After Thermal**
  - **Mating**
    - **Min** ----- 2.72 Lbs
    - **Max** ----- 3.75 Lbs
  - **Unmating**
    - **Min** ----- 2.28 Lbs
    - **Max** ----- 2.92 Lbs

**RESULTS Continued****Mating/Unmating Forces****Mating-Unmating Durability Group (I2SS-05-24-T/T2I-05-VT-T-S-TH)**

- **Initial**
  - **Mating**
    - **Min** ----- 3.84 Lbs
    - **Max** ----- 4.52 Lbs
  - **Unmating**
    - **Min** ----- 3.20 Lbs
    - **Max** ----- 3.35 Lbs
- **After 25 Cycles**
  - **Mating**
    - **Min** ----- 3.12 Lbs
    - **Max** ----- 3.46 Lbs
  - **Unmating**
    - **Min** ----- 2.07 Lbs
    - **Max** ----- 2.34 Lbs
- **After 50 Cycles**
  - **Mating**
    - **Min** ----- 3.08 Lbs
    - **Max** ----- 3.62 Lbs
  - **Unmating**
    - **Min** ----- 1.89 Lbs
    - **Max** ----- 2.12 Lbs
- **After 75 Cycles**
  - **Mating**
    - **Min** ----- 3.14 Lbs
    - **Max** ----- 3.48 Lbs
  - **Unmating**
    - **Min** ----- 1.90 Lbs
    - **Max** ----- 2.12 Lbs
- **After 100 Cycles**
  - **Mating**
    - **Min** ----- 3.04 Lbs
    - **Max** ----- 3.46 Lbs
  - **Unmating**
    - **Min** ----- 1.95 Lbs
    - **Max** ----- 2.06 Lbs
- **Humidity**
  - **Mating**
    - **Min** ----- 2.04 Lbs
    - **Max** ----- 2.31 Lbs
  - **Unmating**
    - **Min** ----- 1.36 Lbs
    - **Max** ----- 1.52 Lbs

**RESULTS Continued****Mating/Unmating Forces****Mating-Unmating Basic (I2SS-02-24-T/T2I-02-VT-T-S-TH)**

- **Initial**
  - **Mating**
    - **Min** ----- 2.31 Lbs
    - **Max** ----- 2.94 Lbs
  - **Unmating**
    - **Min** ----- 1.77 Lbs
    - **Max** ----- 1.90 Lbs
- **After 25 Cycles**
  - **Mating**
    - **Min** ----- 2.41 Lbs
    - **Max** ----- 2.66 Lbs
  - **Unmating**
    - **Min** ----- 1.62 Lbs
    - **Max** ----- 1.77 Lbs
- **After 50 Cycles**
  - **Mating**
    - **Min** ----- 1.69 Lbs
    - **Max** ----- 2.48 Lbs
  - **Unmating**
    - **Min** ----- 1.05 Lbs
    - **Max** ----- 1.17 Lbs
- **After 75 Cycles**
  - **Mating**
    - **Min** ----- 1.60 Lbs
    - **Max** ----- 1.94 Lbs
  - **Unmating**
    - **Min** ----- 0.97 Lbs
    - **Max** ----- 1.07 Lbs
- **After 100 Cycles**
  - **Mating**
    - **Min** ----- 1.66 Lbs
    - **Max** ----- 1.88 Lbs
  - **Unmating**
    - **Min** ----- 1.01 Lbs
    - **Max** ----- 1.08 Lbs

**Normal Force at 0.125 mm deflection****C-386-01**

- **Initial**
  - **Min** ----- 110.00 gf      **Set** ---- 0.0000 mm
  - **Max** ----- 172.10 gf      **Set** ---- 0.0150 mm
- **Thermal**
  - **Min** ----- 118.40 gf      **Set** ---- 0.0000 mm
  - **Max** ----- 168.20 gf      **Set** ---- 0.0225 mm

**C-386-02**

- **Initial**
  - **Min** ----- 183.60 gf      **Set** ---- 0.0000 mm
  - **Max** ----- 257.50 gf      **Set** ---- 0.0129 mm
- **Thermal**
  - **Min** ----- 182.90 gf      **Set** ---- 0.0000 mm
  - **Max** ----- 250.60 gf      **Set** ---- 0.0125 mm

**RESULTS Continued****Insulation Resistance minimums, IR**

- **Initial**
  - Mated-----10000 Meg  $\Omega$ ----- Passed
  - Unmated ----- 10000 Meg  $\Omega$ ----- Passed
- **Thermal Shock**
  - Mated----- 10000 Meg  $\Omega$ ----- Passed
  - Unmated ----- 10000 Meg  $\Omega$ ----- Passed
- **Humidity**
  - Mated-----10000 Meg  $\Omega$ ----- Passed
  - Unmated -----10000 Meg  $\Omega$ ----- Passed

**Dielectric Withstanding Voltage minimums, DWV**

- **Minimums**
  - Breakdown Voltage----- 1000 VAC
  - Test Voltage -----750 VAC
  - Working Voltage ----- 250 VAC
- **Initial DWV**-----Passed
- **Thermal DWV**-----Passed
- **Humidity DWV**-----Passed

**RESULTS Continued****LLCR Thermal Aging Group (40 LLCR test points)**

- **Initial**----- 17.88 mOhms Max
- **Thermal**
  - **<= +5.0 mOhms**----- 40 Points----- Stable
  - **+5.1 to +10.0 mOhms**-----0 Points----- Minor
  - **+10.1 to +15.0 mOhms**-----0 Points----- Acceptable
  - **+15.1 to +50.0 mOhms**-----0 Points----- Marginal
  - **+50.1 to +2000 mOhms**-----0 Points----- Unstable
  - **>+2000 mOhms**-----0 Points----- Open Failure

**LLCR Gas Tight Group (40 LLCR test points)**

- **Initial**----- 17.75 mOhms Max
- **Gas-Tight**
  - **<= +5.0 mOhms**----- 40 Points----- Stable
  - **+5.1 to +10.0 mOhms**-----0 Points----- Minor
  - **+10.1 to +15.0 mOhms**-----0 Points----- Acceptable
  - **+15.1 to +50.0 mOhms**-----0 Points----- Marginal
  - **+50.1 to +2000 mOhms**-----0 Points----- Unstable
  - **>+2000 mOhms**-----0 Points----- Open Failure

**LLCR Mating/Unmating Durability Group (40 LLCR test points)**

- **Initial**----- 18.05 mOhms Max
- **Durability, 100 Cycles**
  - **<= +5.0 mOhms**----- 40 Points----- Stable
  - **+5.1 to +10.0 mOhms**-----0 Points----- Minor
  - **+10.1 to +15.0 mOhms**-----0 Points----- Acceptable
  - **+15.1 to +50.0 mOhms**-----0 Points----- Marginal
  - **+50.1 to +2000 mOhms**-----0 Points----- Unstable
  - **>+2000 mOhms**-----0 Points----- Open Failure
- **Thermal Shock**
  - **<= +5.0 mOhms**----- 40 Points----- Stable
  - **+5.1 to +10.0 mOhms**-----0 Points----- Minor
  - **+10.1 to +15.0 mOhms**-----0 Points----- Acceptable
  - **+15.1 to +50.0 mOhms**-----0 Points----- Marginal
  - **+50.1 to +2000 mOhms**-----0 Points----- Unstable
  - **>+2000 mOhms**-----0 Points----- Open Failure
- **Humidity**
  - **<= +5.0 mOhms**----- 11 Points----- Stable
  - **+5.1 to +10.0 mOhms**----- 28 Points----- Minor
  - **+10.1 to +15.0 mOhms**----- 1 Points----- Acceptable
  - **+15.1 to +50.0 mOhms**----- 0 Points----- Marginal
  - **+50.1 to +2000 mOhms**----- 0 Points----- Unstable
  - **>+2000 mOhms**----- 0 Points----- Open Failure

**RESULTS Continued****LLCR Shock & Vibration Group (40 LLCR test points)**

- **Initial**----- 28.98 mOhms Max
- **Shock & Vibration**
  - **<= +5.0 mOhms** ----- 40 Points ----- **Stable**
  - **+5.1 to +10.0 mOhms** ----- 0 Points ----- **Minor**
  - **+10.1 to +15.0 mOhms** ----- 0 Points ----- **Acceptable**
  - **+15.1 to +50.0 mOhms** ----- 0 Points ----- **Marginal**
  - **+50.1 to +2000 mOhms** ----- 0 Points ----- **Unstable**
  - **>+2000 mOhms** ----- 0 Points ----- **Open Failure**

**Mechanical Shock & Random Vibration:**

- **Shock**
  - **No Damage**----- **Pass**
  - **50 Nanoseconds**----- **Pass**
- **Vibration**
  - **No Damage**----- **Pass**
  - **50 Nanoseconds**----- **Pass**

**Cable Pull**

- **0 ° Pull force**
  - **Min**-----17.90 Lbs
  - **Max**-----20.38 Lbs
- **90 ° Pull force**
  - **Min**-----5.60 Lbs
  - **Max**-----6.27 Lbs

**Cable Flex****IR**

- **Initial**
  - **Mated**-----45000 Meg  $\Omega$  ----- **Passed**
- **After 500 Flex cycles**
  - **Mated**-----45000 Meg  $\Omega$  ----- **Passed**

**DWV**

- **Initial DWV**----- **Passed**
- **500 Flex cycles DWV**-----**Passed**

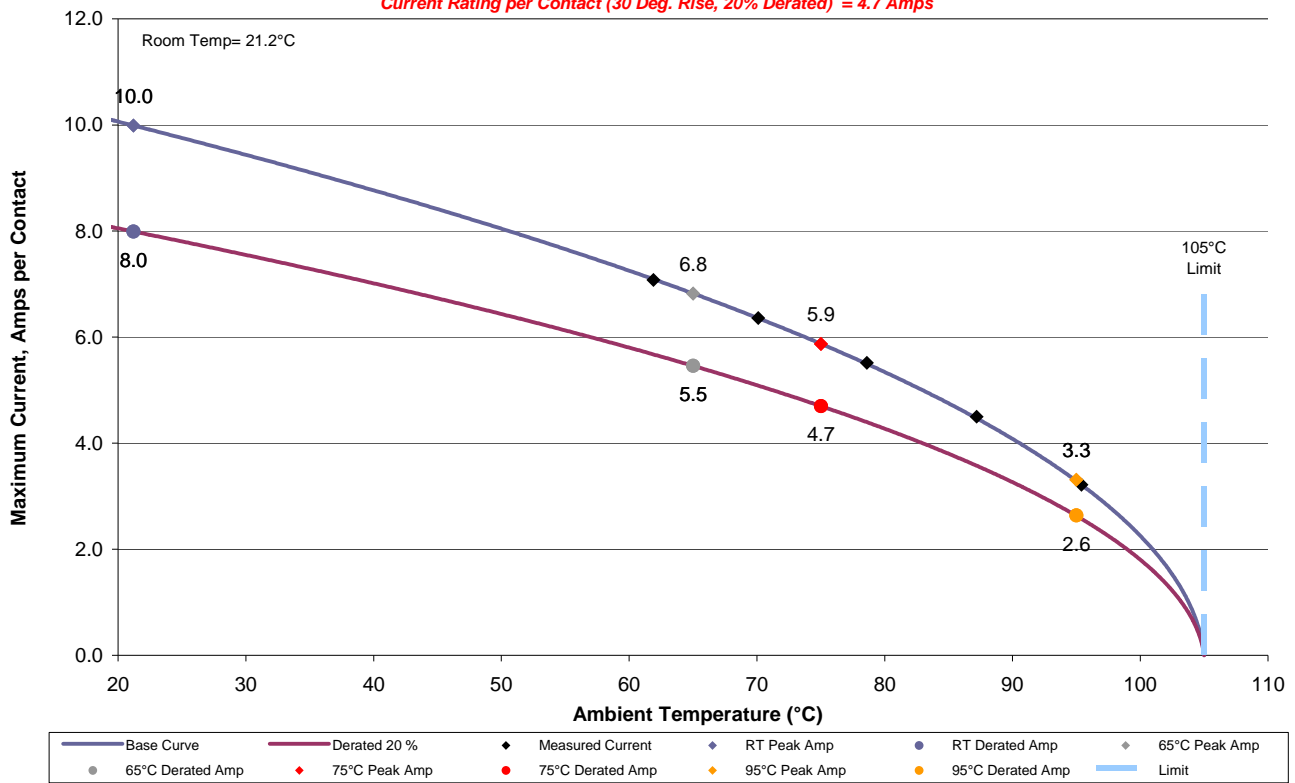
### DATA SUMMARIES

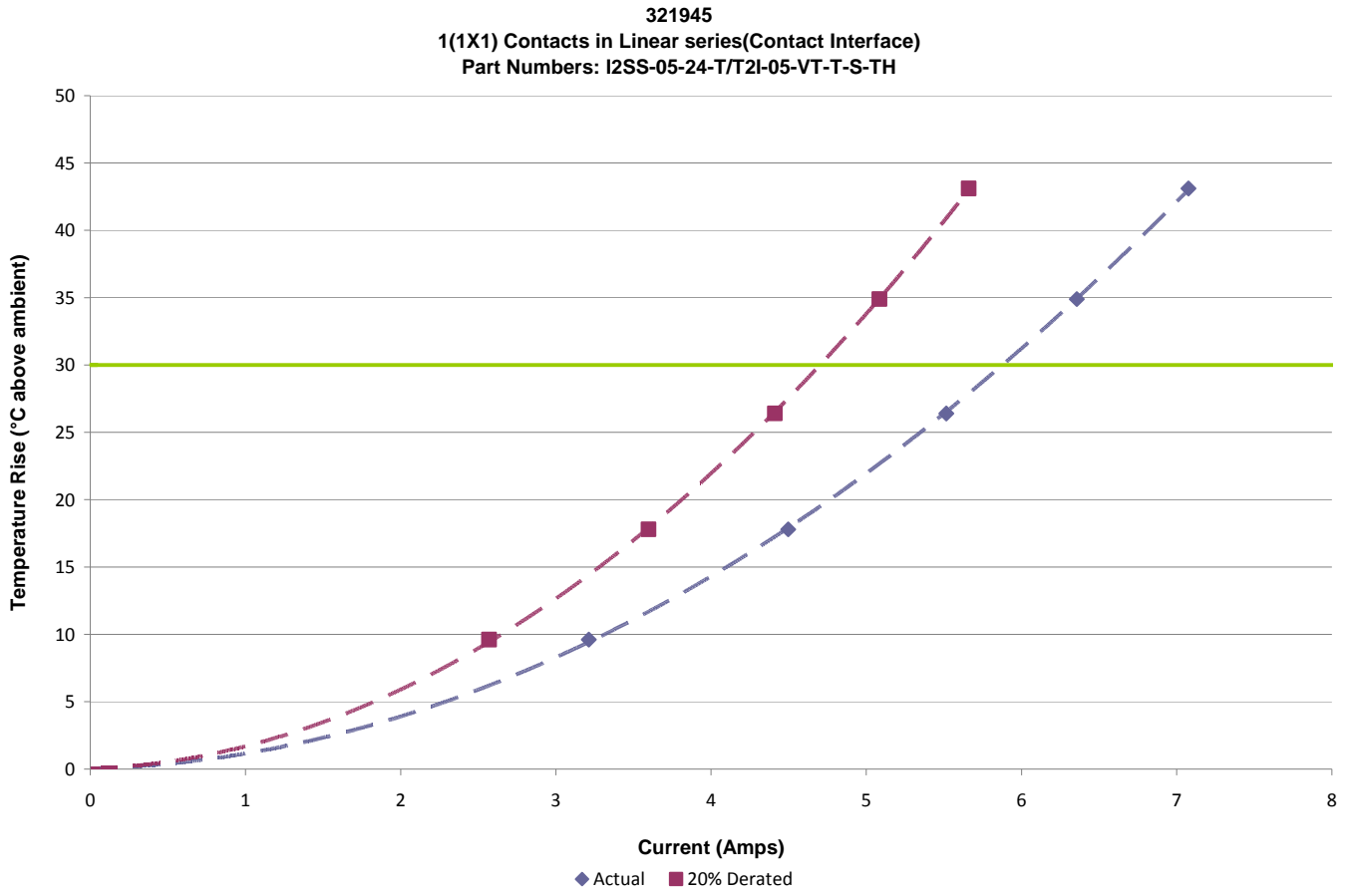
#### TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
  - a. Linear configuration with 1 adjacent conductors/contacts powered

321945  
 1(1X1) Contacts in Linear series(Contact Interface)  
 Part Numbers: I2SS-05-24-T/T2I-05-VT-T-S-TH

Current Rating per Contact (30 Deg. Rise, 20% Derated) = 4.7 Amps



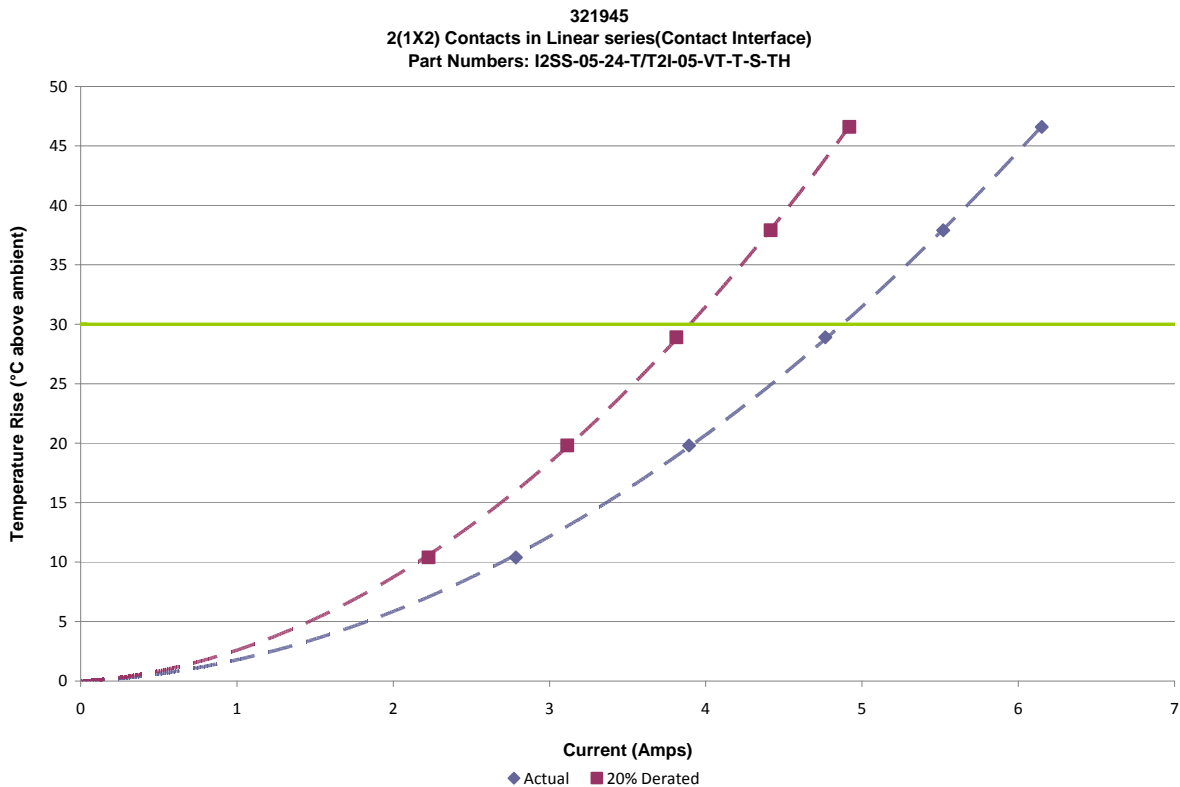
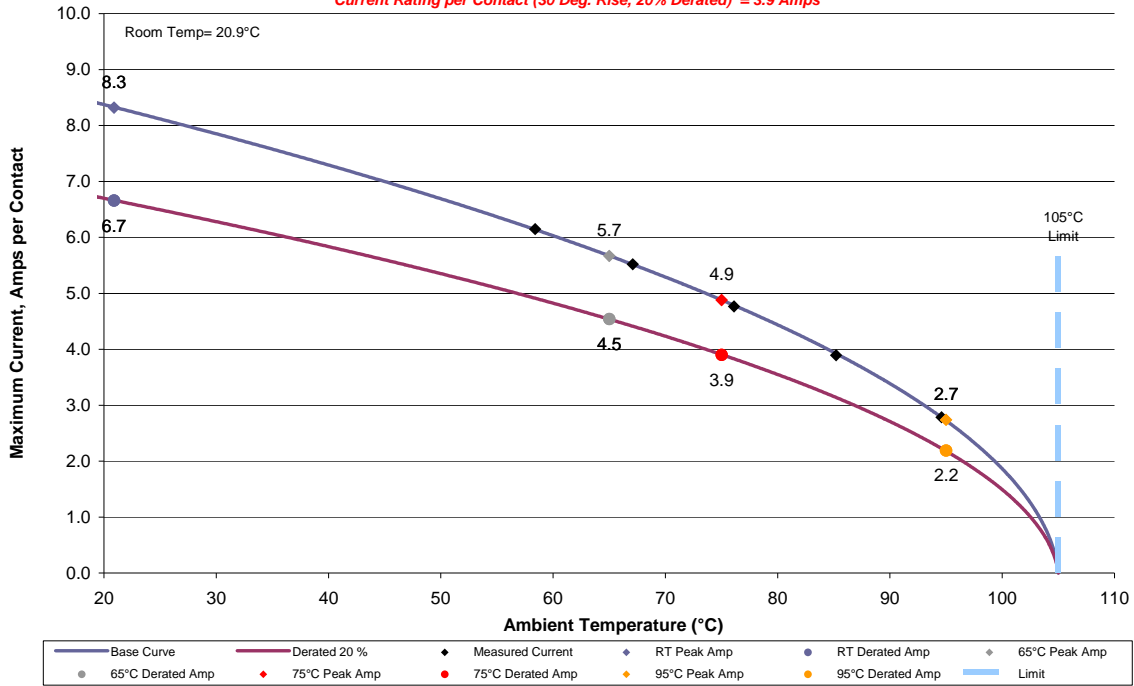


### DATA SUMMARIES Continued

#### b. Linear configuration with 2 adjacent conductors/contacts powered

321945  
 2(1X2) Contacts in Linear series(Contact Interface)  
 Part Numbers: I2SS-05-24-T/T2I-05-VT-T-S-TH

Current Rating per Contact (30 Deg. Rise, 20% Derated) = 3.9 Amps

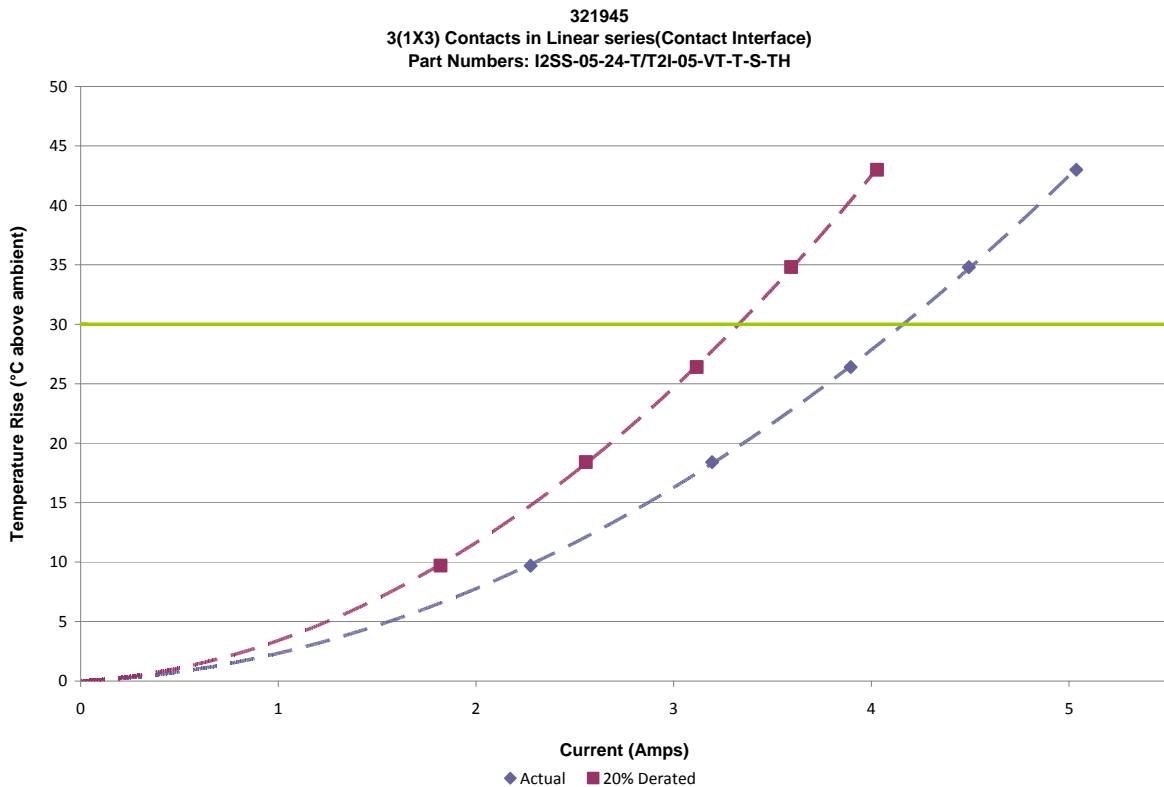
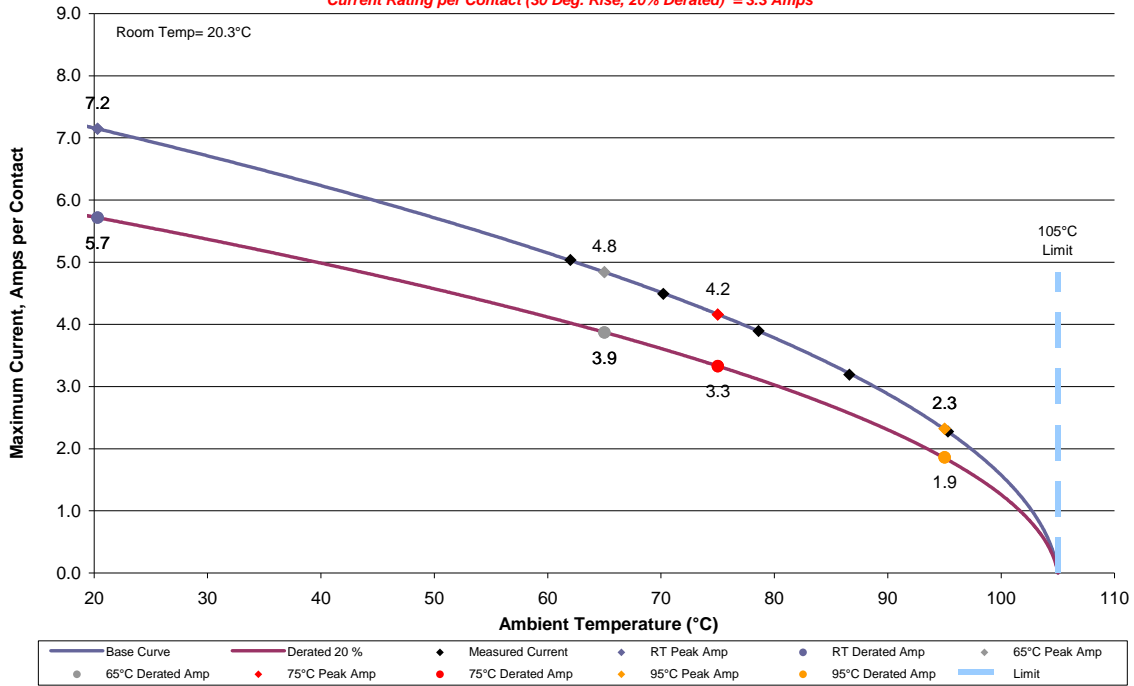


### DATA SUMMARIES Continued

c. Linear configuration with 3 adjacent conductors/contacts powered

321945  
 3(1X3) Contacts in Linear series(Contact Interface)  
 Part Numbers: I2SS-05-24-T/T2I-05-VT-T-S-TH

Current Rating per Contact (30 Deg. Rise, 20% Derated) = 3.3 Amps

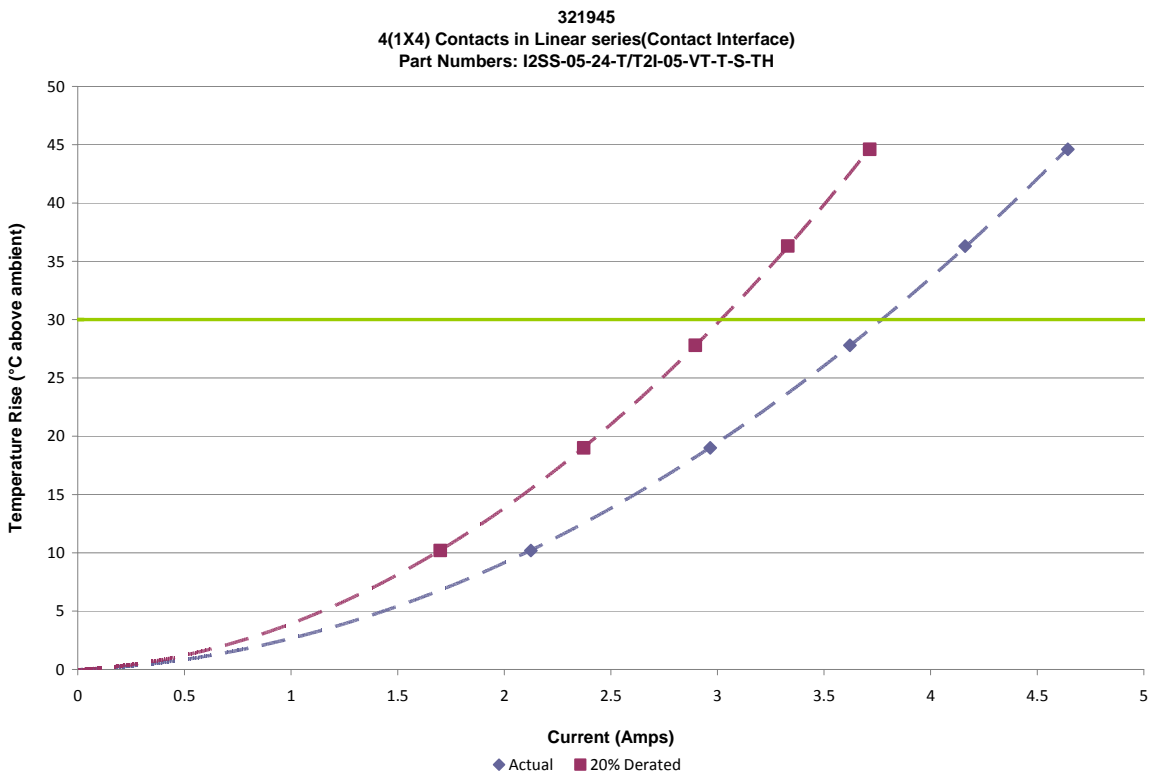
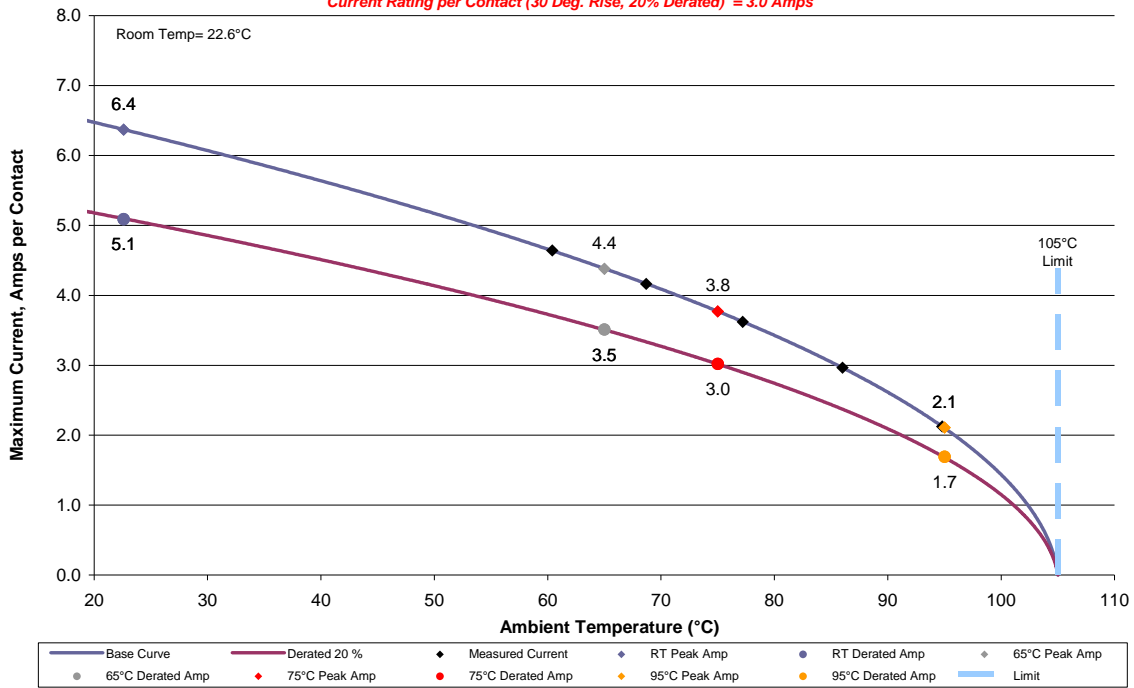


### DATA SUMMARIES Continued

d. Linear configuration with 4 adjacent conductors/contacts powered

321945  
 4(1X4) Contacts in Linear series(Contact Interface)  
 Part Numbers: I2SS-05-24-T/T2I-05-VT-T-S-TH

*Current Rating per Contact (30 Deg. Rise, 20% Derated) = 3.0 Amps*

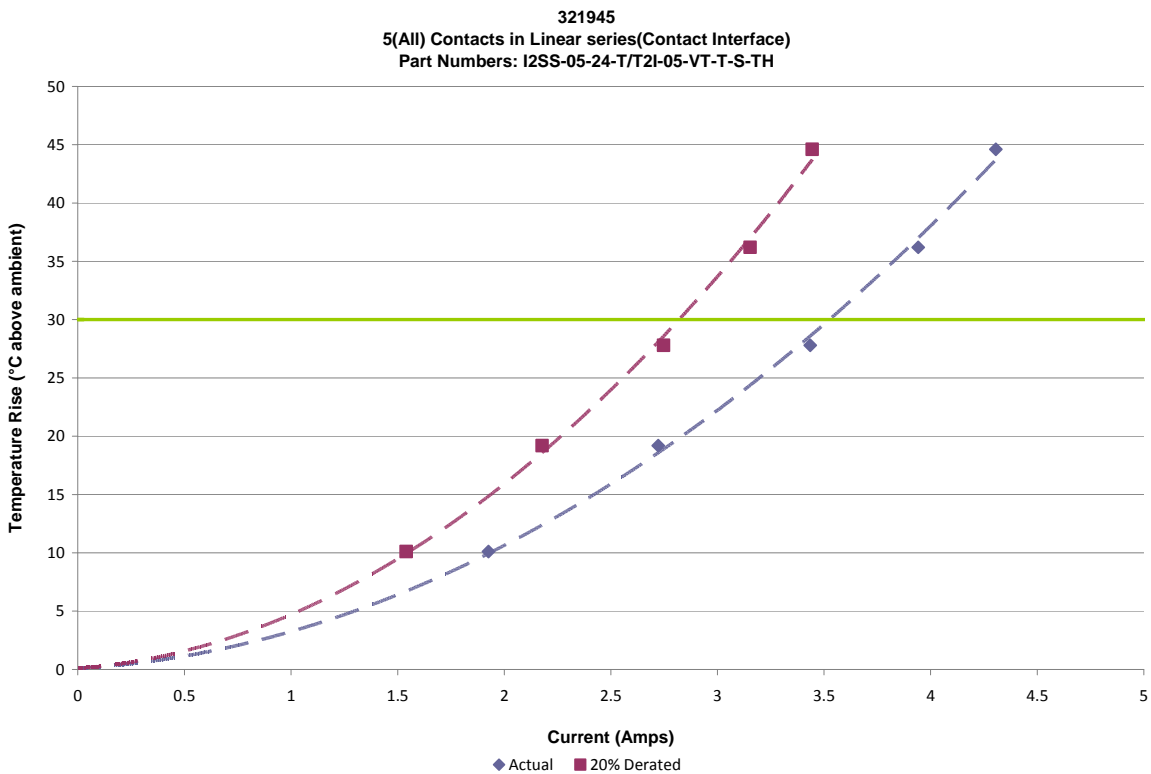
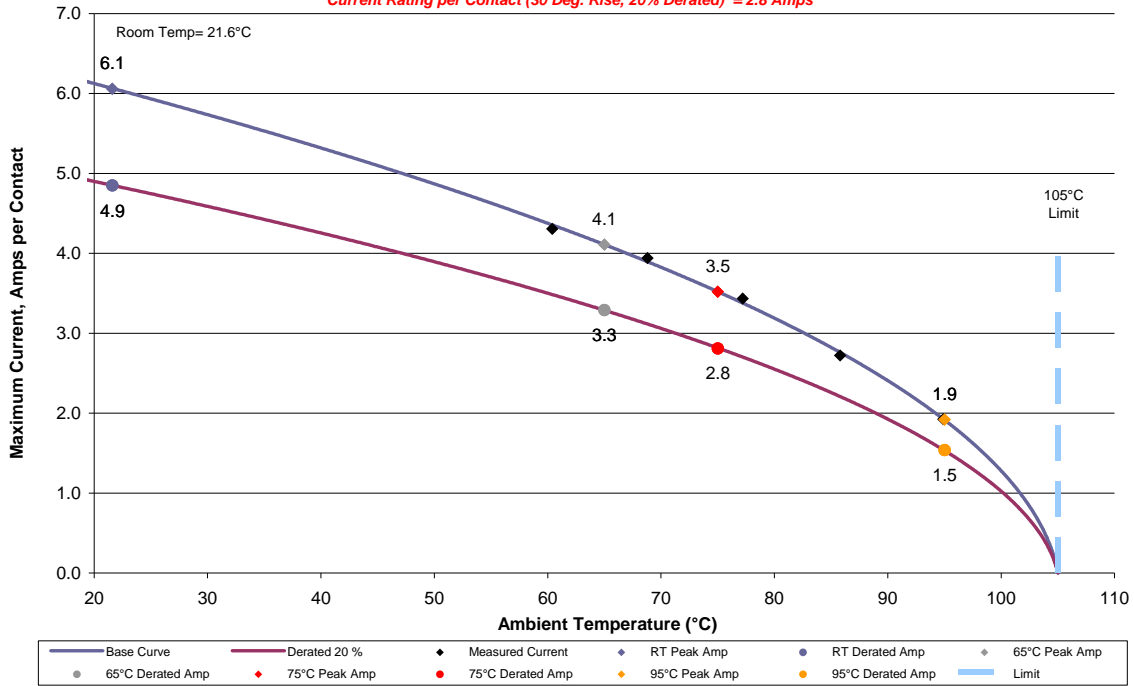


### DATA SUMMARIES Continued

e. Linear configuration with all adjacent conductors/contacts powered

321945  
 5(All) Contacts in Linear series(Contact Interface)  
 Part Numbers: I2SS-05-24-T/T2I-05-VT-T-S-TH

*Current Rating per Contact (30 Deg. Rise, 20% Derated) = 2.8 Amps*



**DATA SUMMARIES Continued****MATING-UNMATING FORCE:**  
**Thermal Aging Group**

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	19.26	4.33	14.99	3.37	12.10	2.72	10.14	2.28
Maximum	20.10	4.52	16.77	3.77	16.68	3.75	12.99	2.92
<b>Average</b>	19.69	<b>4.43</b>	15.74	<b>3.54</b>	14.09	<b>3.17</b>	11.30	<b>2.54</b>
St Dev	0.28	0.06	0.64	0.14	1.62	0.36	0.97	0.22
Count	8	8	8	8	8	8	8	8

**Mating-Unmating Durability Group (I2SS-05-24-T/T2I-05-VT-T-S-TH)**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	17.08	3.84	14.23	3.20	13.88	3.12	9.21	2.07
Maximum	20.10	4.52	14.90	3.35	15.39	3.46	10.41	2.34
<b>Average</b>	18.21	<b>4.10</b>	14.68	<b>3.30</b>	14.42	<b>3.24</b>	9.65	<b>2.17</b>
St Dev	0.96	0.21	0.21	0.05	0.51	0.12	0.40	0.09
Count	8	8	8	8	8	8	8	8

	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	13.70	3.08	8.41	1.89	13.97	3.14	8.45	1.90
Maximum	16.10	3.62	9.43	2.12	15.48	3.48	9.43	2.12
<b>Average</b>	14.67	<b>3.30</b>	8.97	<b>2.02</b>	14.46	<b>3.25</b>	8.87	<b>2.00</b>
St Dev	0.72	0.16	0.34	0.08	0.49	0.11	0.32	0.07
Count	8	8	8	8	8	8	8	8

	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	13.52	3.04	8.67	1.95	9.07	2.04	6.05	1.36
Maximum	15.39	3.46	9.16	2.06	10.27	2.31	6.76	1.52
<b>Average</b>	14.48	<b>3.26</b>	8.93	<b>2.01</b>	9.44	<b>2.12</b>	6.38	<b>1.44</b>
St Dev	0.60	0.13	0.16	0.04	0.39	0.09	0.26	0.06
Count	8	8	8	8	8	8	8	8

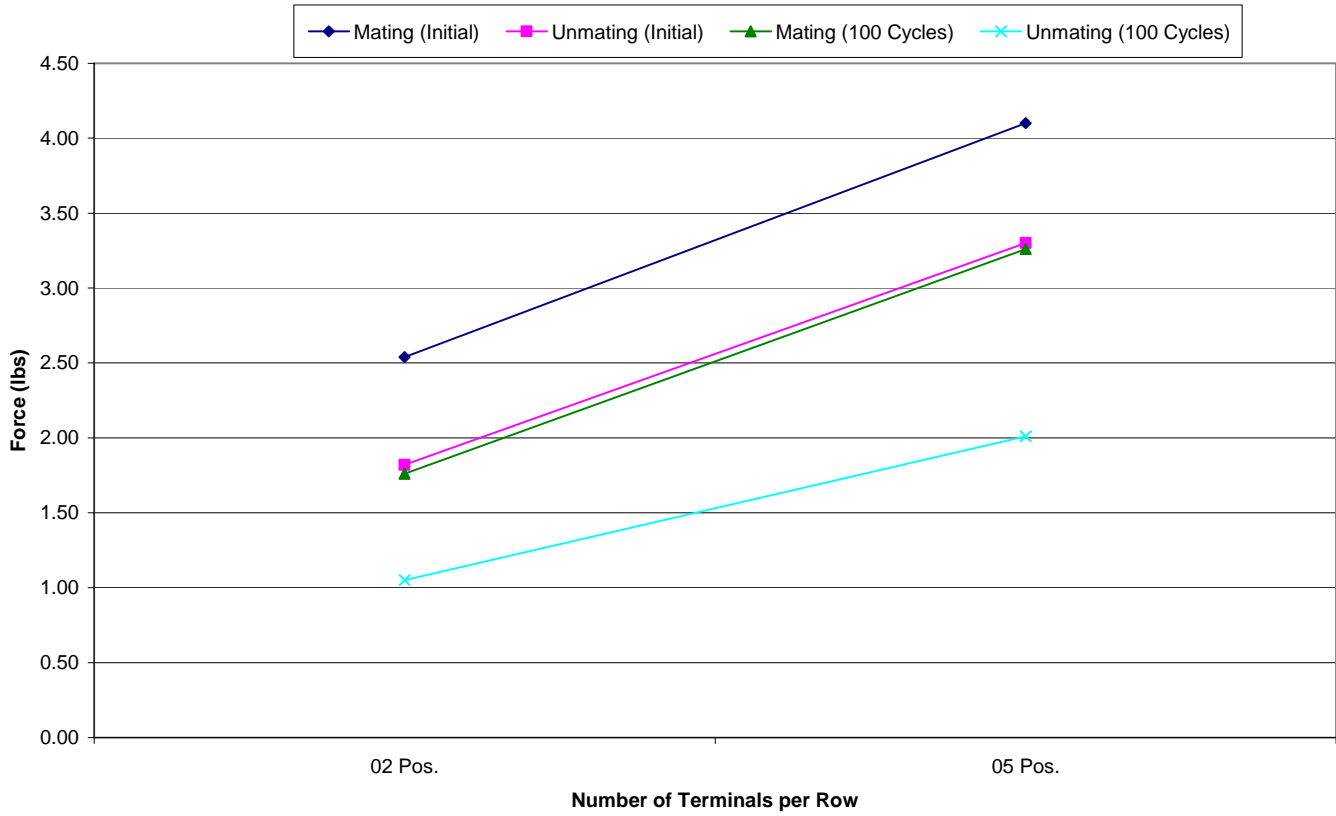
**DATA SUMMARIES Continued****MATING-UNMATING FORCE:****Mating-Unmating Basic (I2SS-02-24-T/T2I-02-VT-T-S-TH)**

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	10.27	2.31	7.87	1.77	10.72	2.41	7.21	1.62
Maximum	13.08	2.94	8.45	1.90	11.83	2.66	7.87	1.77
<b>Average</b>	11.30	<b>2.54</b>	8.10	<b>1.82</b>	11.43	<b>2.57</b>	7.52	<b>1.69</b>
St Dev	0.89	0.20	0.17	0.04	0.39	0.09	0.24	0.05
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)	Newton's	Force (Lbs)
Minimum	7.52	1.69	4.67	1.05	7.12	1.60	4.31	0.97
Maximum	11.03	2.48	5.20	1.17	8.63	1.94	4.76	1.07
<b>Average</b>	8.60	<b>1.93</b>	4.86	<b>1.09</b>	7.75	<b>1.74</b>	4.58	<b>1.03</b>
St Dev	1.12	0.25	0.22	0.05	0.61	0.14	0.13	0.03
Count	8	8	8	8	8	8	8	8
	After 100 Cycles							
	Mating		Unmating					
	Newton's	Force (Lbs)	Newton's	Force (Lbs)				
Minimum	7.38	1.66	4.49	1.01				
Maximum	8.36	1.88	4.80	1.08				
<b>Average</b>	7.81	<b>1.76</b>	4.65	<b>1.05</b>				
St Dev	0.30	0.07	0.10	0.02				
Count	8	8	8	8				

### DATA SUMMARIES Continued

#### Mating\Unmating Force Comparison

Mating/Unmating Data for 02 and 05 Position I2SS/T2I



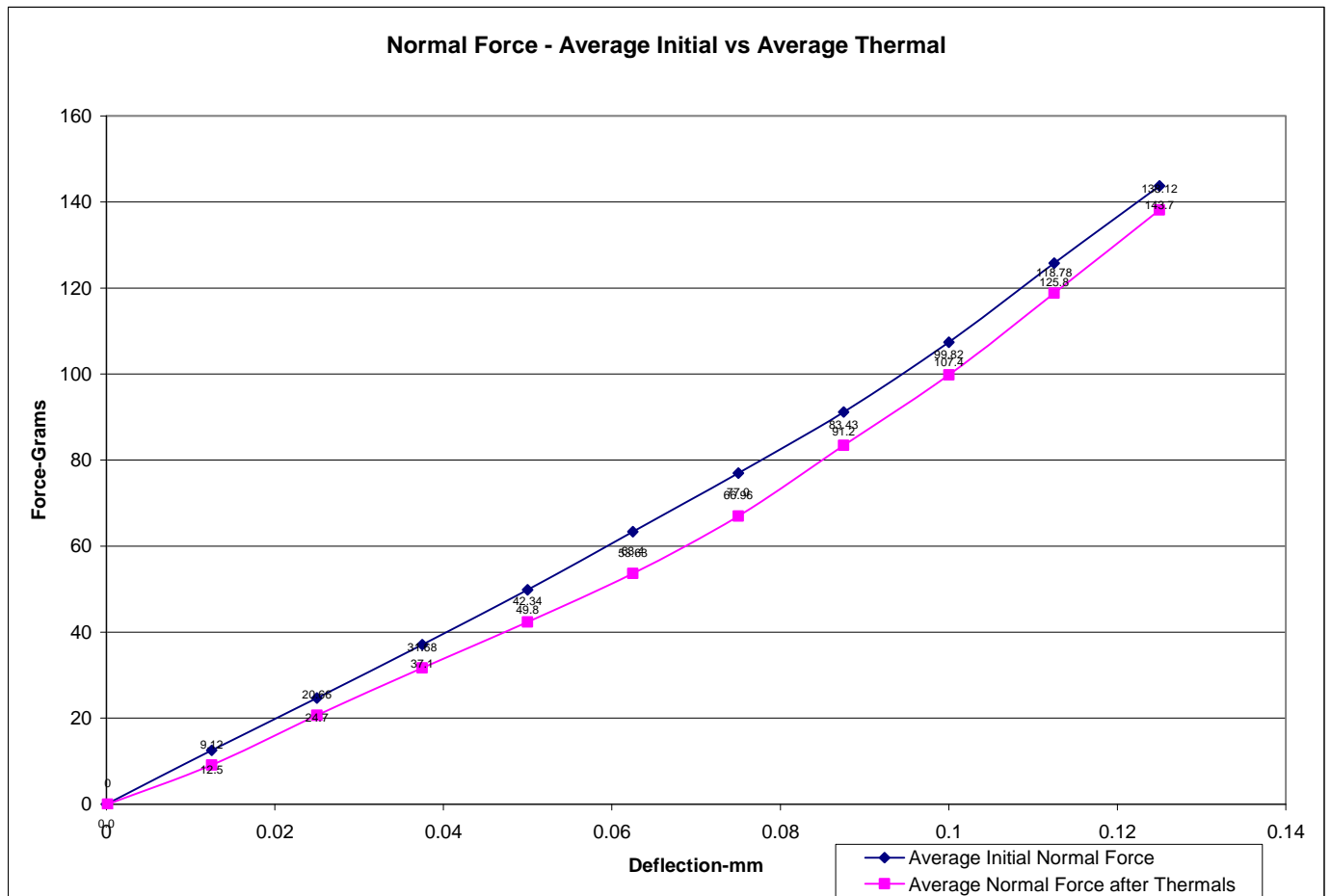
**DATA SUMMARIES Continued****NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):**

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

**C-386-01**

Initial	Deflections in mm Forces in Grams										
	<b>0.0125</b>	<b>0.0250</b>	<b>0.0375</b>	<b>0.0500</b>	<b>0.0625</b>	<b>0.0750</b>	<b>0.0875</b>	<b>0.1000</b>	<b>0.1125</b>	<b>0.1250</b>	<b>SET</b>
<b>Averages</b>	12.52	24.68	37.08	49.84	63.37	76.96	91.16	107.41	125.80	143.73	0.0070
<b>Min</b>	8.50	19.40	30.60	44.10	54.70	65.20	77.50	89.80	98.70	111.00	0.0000
<b>Max</b>	18.70	34.20	51.70	67.40	86.40	106.60	125.90	143.90	164.70	172.10	0.0150
<b>St. Dev</b>	2.646	4.927	6.863	8.537	11.066	13.763	15.972	17.534	19.520	18.295	0.0049
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in mm Forces in Grams										
	<b>0.0125</b>	<b>0.0250</b>	<b>0.0375</b>	<b>0.0500</b>	<b>0.0625</b>	<b>0.0750</b>	<b>0.0875</b>	<b>0.1000</b>	<b>0.1125</b>	<b>0.1250</b>	<b>SET</b>
<b>Averages</b>	9.12	20.66	31.68	42.34	53.63	66.96	83.43	99.82	118.78	138.12	0.0098
<b>Min</b>	3.40	16.60	26.00	30.10	42.70	47.80	65.30	78.80	99.50	118.40	0.0000
<b>Max</b>	13.10	26.00	37.60	54.90	70.80	90.90	110.10	126.30	146.90	168.20	0.0225
<b>St. Dev</b>	3.696	2.927	4.135	7.449	9.754	12.891	14.099	15.161	15.269	16.825	0.0090
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12



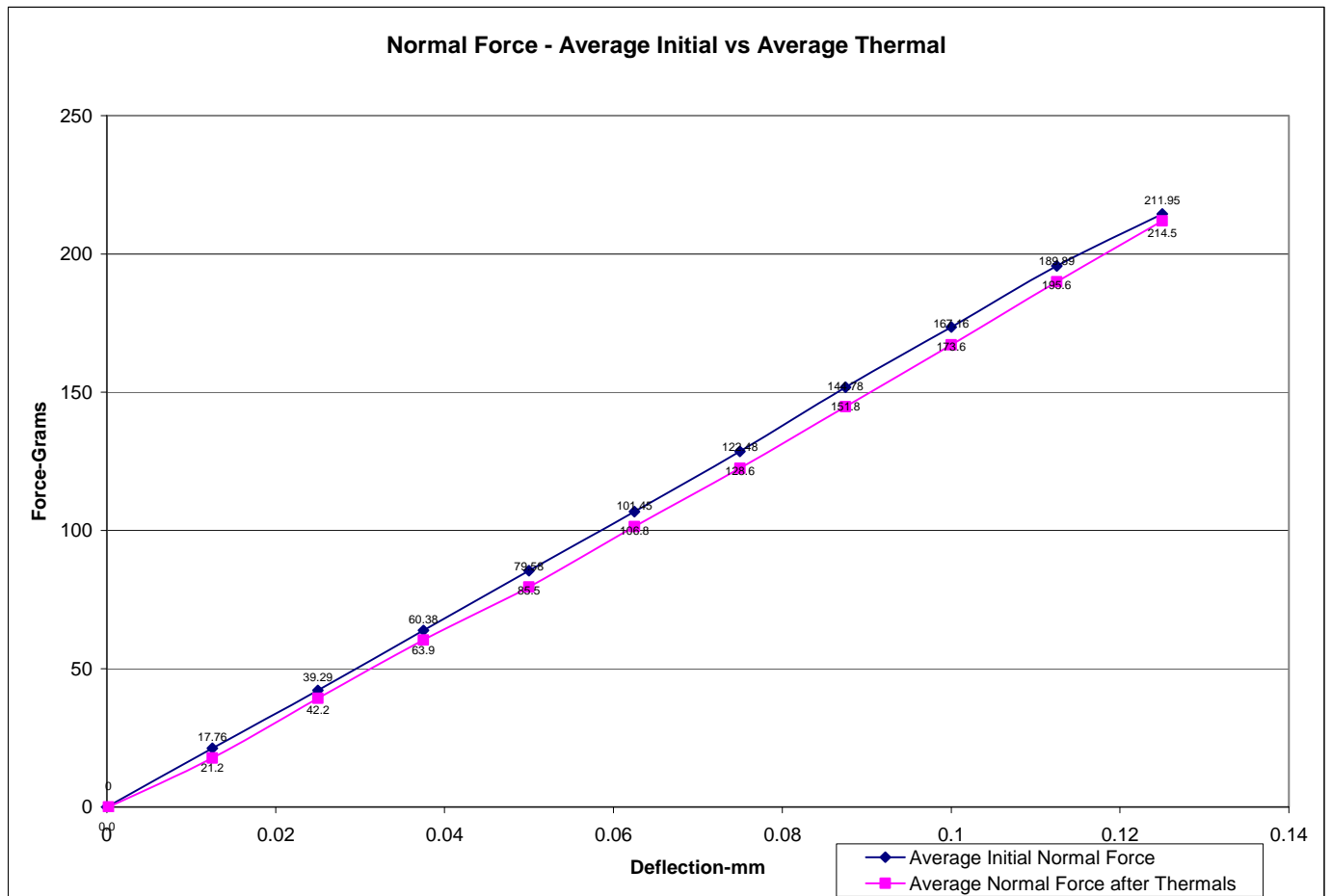
**DATA SUMMARIES Continued****NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):**

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

**C-386-02**

Initial	Deflections in mm Forces in Grams										
	<b>0.0125</b>	<b>0.0250</b>	<b>0.0375</b>	<b>0.0500</b>	<b>0.0625</b>	<b>0.0750</b>	<b>0.0875</b>	<b>0.1000</b>	<b>0.1125</b>	<b>0.1250</b>	<i>SET</i>
<b>Averages</b>	21.23	42.21	63.85	85.48	106.83	128.61	151.79	173.55	195.63	214.48	0.0053
<b>Min</b>	17.90	34.00	53.70	73.90	93.40	109.50	132.70	151.60	171.60	183.60	0.0000
<b>Max</b>	26.80	52.50	75.40	100.60	127.10	158.80	187.60	213.10	244.70	257.50	0.0129
<b>St. Dev</b>	3.040	6.798	8.276	10.065	12.740	16.693	18.521	20.502	24.200	23.865	0.0043
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in mm Forces in Grams										
	<b>0.0125</b>	<b>0.0250</b>	<b>0.0375</b>	<b>0.0500</b>	<b>0.0625</b>	<b>0.0750</b>	<b>0.0875</b>	<b>0.1000</b>	<b>0.1125</b>	<b>0.1250</b>	<i>SET</i>
<b>Averages</b>	17.76	39.29	60.38	79.58	101.45	122.48	144.78	167.16	189.89	211.95	0.0050
<b>Min</b>	10.40	33.60	50.70	61.00	75.80	92.80	115.50	139.30	159.70	182.90	0.0000
<b>Max</b>	26.90	52.80	75.70	100.10	125.60	151.00	173.90	199.00	224.90	250.60	0.0125
<b>St. Dev</b>	4.520	5.556	8.118	11.488	14.591	17.166	18.070	19.248	20.159	22.239	0.0054
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12



**DATA SUMMARIES Continued****INSULATION RESISTANCE (IR):**

	Pin to Pin		
	Mated	Unmated	Unmated
Minimum	I2SS/T2I	I2SS	T2I
<b>Initial</b>	10000	10000	10000
<b>Thermal</b>	10000	10000	10000
<b>Humidity</b>	10000	10000	10000

**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

Voltage Rating Summary	
Minimum	I2SS/T2I
<b>Break Down Voltage</b>	1000
<b>Test Voltage</b>	750
<b>Working Voltage</b>	250

Pin to Pin	
<b>Initial Test Voltage</b>	Passed
<b>After Thermal Test Voltage</b>	Passed
<b>After Humidity Test Voltage</b>	Passed

**DATA SUMMARIES Continued****LLCR Thermal Aging Group**

- 1) A total of 40 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: -----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: -----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: -----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: -----Marginal
  - e.  $+50.1$  to  $+2000$  mOhms: -----Unstable
  - f.  $>+2000$  mOhms: -----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	3/25/2014	4/8/2014		
Room Temp (Deg C)	21	21		
Rel Humidity (%)	53	55		
Technician	Kason He	Kason He		
<b>mOhm values</b>	<b>Actual</b>	<b>Delta</b>	<b>Delta</b>	<b>Delta</b>
	<b>Initial</b>	<b>Thermal</b>		
<b>Pin Type 1: Signal</b>				
Average	17.32	0.21		
St. Dev.	0.27	0.21		
Min	16.81	0.02		
Max	17.88	0.89		
Summary Count	40	40		
Total Count	40	40		

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
<b>mOhms</b>	$\leq 5$	$>5 \ \& \ \leq 10$	$>10 \ \& \ \leq 15$	$>15 \ \& \ \leq 50$	$>50 \ \& \ \leq 1000$	$>1000$
<b>Thermal</b>	<b>40</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>

**DATA SUMMARIES Continued****LLCR Mating/Unmating Durability Group**

- 1). A total of 40 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). A computer program, *LLCR 22I.exe*, ensures repeatability for data acquisition.
- 4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: -----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: -----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: -----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: -----Marginal
  - e.  $+50.1$  to  $+2000$  mOhms -----Unstable
  - f.  $> +2000$  mOhms: -----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	3/21/2014	3/26/2014	3/31/2014	4/14/2014
Room Temp (Deg C)	21	21	21	21
Rel Humidity (%)	49	53	59	58
Technician	Kason He	Kason He	Kason He	Kason He
<b>mOhm values</b>	<b>Actual Initial</b>	<b>Delta 100 Cycles</b>	<b>Delta Therm Shck</b>	<b>Delta Humidity</b>
<b>Pin Type 1: Signal</b>				
Average	17.27	1.31	1.68	6.63
St. Dev.	0.32	0.72	0.92	2.11
Min	16.64	0.35	0.57	1.59
Max	18.05	2.64	4.68	10.21
Summary Count	40	40	40	40
Total Count	40	40	40	40

<b>LLCR Delta Count by Category</b>						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	$\leq 5$	$>5 \ \& \ \leq 10$	$>10 \ \& \ \leq 15$	$>15 \ \& \ \leq 50$	$>50 \ \& \ \leq 1000$	$>1000$
<b>100 Cycles</b>	40	0	0	0	0	0
<b>Therm Shck</b>	40	0	0	0	0	0
<b>Humidity</b>	11	28	1	0	0	0

**DATA SUMMARIES Continued****LLCR Gas Tight Group**

- 1) A total of 40 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms:-----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:-----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:-----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:-----Marginal
  - e.  $+50.1$  to  $+2000$  mOhms:-----Unstable
  - f.  $>+2000$  mOhms:-----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	4/25/2014	4/30/2014		
Room Temp (Deg C)	22	22		
Rel Humidity (%)	58	54		
Technician	Kason He	Kason He		
<b>mOhm values</b>	<b>Actual Initial</b>	<b>Delta Acid Vapor</b>	<b>Delta</b>	<b>Delta</b>
<b>Pin Type 1: Signal</b>				
Average	17.22	0.14		
St. Dev.	0.31	0.11		
Min	16.47	0.00		
Max	17.75	0.61		
Summary Count	40	40		
Total Count	40	40		

<b>LLCR Delta Count by Category</b>						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	$\leq 5$	$>5$ & $\leq 10$	$>10$ & $\leq 15$	$>15$ & $\leq 50$	$>50$ & $\leq 1000$	$>1000$
<b>Acid Vapor</b>	<b>40</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>

**DATA SUMMARIES Continued**

**LLCR Shock & Vibration Group**

- 1) A total of 40 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: -----Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: -----Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: -----Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: -----Marginal
  - e.  $+50.1$  to  $+2000$  mOhms-----Unstable
  - f.  $>+2000$  mOhms: -----Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	4/16/2014	5/6/2014		
Room Temp (Deg C)	23	22		
Rel Humidity (%)	32	36		
Technician	Troy Cook	Troy Cook		
<b>mOhm values</b>	<b>Actual Initial</b>	<b>Delta Shock-Vib</b>	<b>Delta</b>	<b>Delta</b>
<b>Pin Type 1: Signal</b>				
Average	28.25	0.18		
St. Dev.	0.46	0.35		
Min	27.24	0.00		
Max	28.98	2.03		
Summary Count	40	40		
Total Count	40	40		

<b>LLCR Delta Count by Category</b>						
	<b>Stable</b>	<b>Minor</b>	<b>Acceptable</b>	<b>Marginal</b>	<b>Unstable</b>	<b>Open</b>
<b>mOhms</b>	<b><math>\leq 5</math></b>	<b><math>&gt;5 \ \&amp; \ \leq 10</math></b>	<b><math>&gt;10 \ \&amp; \ \leq 15</math></b>	<b><math>&gt;15 \ \&amp; \ \leq 50</math></b>	<b><math>&gt;50 \ \&amp; \ \leq 1000</math></b>	<b><math>&gt;1000</math></b>
<b>Shock-Vib</b>	<b>40</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>	<b>0</b>

**Nanosecond Event Detection:**

<b>Shock and Vibration Event Detection Summary</b>	
Contacts tested	32
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
<b>Total Events</b>	<b>0</b>

**DATA SUMMARIES Continued****Cable Pull****0 ° Pull force**

	Force (lbs)
Minimum	<b>17.90</b>
Maximum	20.38
Average	19.53

**90 ° Pull force**

	Force (lbs)
Minimum	<b>5.60</b>
Maximum	6.27
Average	5.93

**Cable Flex****IR**

<b>Pin to Pin</b>	
Mated	
Minimum	
<b>Initial</b>	45000
<b>After 500 Flex Cycles</b>	45000

**DWV**

<b>Pin to Pin</b>	
<b>Initial Test Voltage</b>	Passed
<b>After 500 Flex Cycles Test Voltage</b>	Passed

**EQUIPMENT AND CALIBRATION SCHEDULES****Equipment #:** HZ-TCT-01**Description:** Normal force analyzer**Manufacturer:** Mecmesin Multitester**Model:** Mecmesin Multitester 2.5-i**Serial #:** 08-1049-04**Accuracy:** Last Cal: 4/26/2013, Next Cal: 4/25/2014**Equipment #:** HZ-OV-01**Description:** Oven**Manufacturer:** Huida**Model:** CS101-1E**Serial #:** CS101-1E-B**Accuracy:** Last Cal: 12/12/2013, Next Cal: 12/11/2014**Equipment #:** HZ-THC-01**Description:** Humidity transmitter**Manufacturer:** Thermtron**Model:** SM-8-8200**Serial #:** 38846**Accuracy:** Last Cal: 2/27/2014, Next Cal: 2/26/2015**Equipment #:** HZ-HPM-01**Description:** NA9636H**Manufacturer:** Ainuo**Model:** 6031A**Serial #:** 089601091**Accuracy:** Last Cal: 3/6/2014, Next Cal: 3/5/2015**Equipment #:** HZ-MO-05**Description:** Micro-ohmmeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 1285188**Accuracy:** Last Cal: 11/14/2013, Next Cal: 11/13/2014**Equipment #:** HZ-TSC-01**Description:** Vertical Thermal Shock Chamber**Manufacturer:** Cincinnatti Sub Zero**Model:** VTS-3-6-6-SC/AC**Serial #:** 10-VT14994**Accuracy:** See Manual

... Last Cal: 06/27/2013, Next Cal: 06/26/2014

**Equipment #:** HZ-PS-01**Description:** 120 Amp Power Supply**Manufacturer:** Agilent**Model:** 6031A PS**Serial #:** MY41000982**Accuracy:** See Manual

... Last Cal: 07/02/2013, Next Cal: 07/01/2014

**EQUIPMENT AND CALIBRATION SCHEDULES Continued****Equipment #:** HZ-MO-01**Description:** Multimeter /Data Acquisition System**Manufacturer:** Keithley**Model:** 2700**Serial #:** 1199807**Accuracy:** See Manual

... Last Cal: 07/02/2013, Next Cal: 07/01/2014

**Equipment #:** MO-11**Description:** Switch/Multimeter**Manufacturer:** Keithley**Model:** 3706**Serial #:** 120169**Accuracy:** See Manual

... Last Cal: 08/21/2013, Next Cal: 08/21/2014

**Equipment #:** SVC-01**Description:** Shock & Vibration Table**Manufacturer:** Data Physics**Model:** LE-DSA-10-20K**Serial #:** 10037**Accuracy:** See Manual

... Last Cal: 11/31/2013, Next Cal: 11/31/2014

**Equipment #:** ACLM-01**Description:** Accelerometer**Manufacturer:** PCB Piezotronics**Model:** 352C03**Serial #:** 115819**Accuracy:** See Manual

... Last Cal: 07/09/2014, Next Cal: 07/09/2014

**Equipment #:** ED-03**Description:** Event Detector**Manufacturer:** Analysis Tech**Model:** 32EHD**Serial #:** 1100604**Accuracy:** See Manual

... Last Cal: 06/04/2013, Next Cal: 06/04/2014